



New GI2.5 Receptacle Contact 1971795-1 Qualified Report

1. INTRODUCTION

1.1. Purpose

Testing was performed on the TE Connectivity (TE) Next Generation GRACE INERTIA* 2.5 Series receptacle contact P/N 1971795-1 to determine its conformance to the requirements of 108-106077, Revision D.

1.2. Scope

This report covers the electrical, mechanical, and environmental performance of Next Generation GRACE INERTIA* (GI) 2.5 Series Connectors. Testing was performed at the Shanghai Electrical Components Test Laboratory between 28Apr2019 and 17May17. The test file number for this testing is on file and maintained at the TE Shanghai Electrical Components Test Laboratory under TP-19-00880-RECORD& TP-19-02172-RECORD.

1.3. Conclusion

All part numbers listed in paragraph 1.5 conformed to the electrical, mechanical, and environmental performance requirements of Product Specification 108-106077, Revision D.

1.4. Product Description

The New Generation GRACE INERTIA* 2.5 Series Connectors are designed to accept 22 – 28 AWG wires and are available in 2 – 8 position configurations

1.5. Test Specimens

The test specimens were representative of normal production lots, and the following part numbers were used for testing (See Table 1).

Table 1 – Specimen Identification

Test Group	Qty	Part Number	Description
1	10	1971795-1	Receptacle Contact 2.5 Pitch Next Generation GI Connector 2.5, 22 AWG
	10	1971795-1	Receptacle Contact 2.5 Pitch Next Generation GI Connector 2.5, 24 AWG
	10	1971795-1	Receptacle Contact 2.5 Pitch Next Generation GI Connector 2.5, 26 AWG
	10	1971795-1	Receptacle Contact 2.5 Pitch Next Generation GI Connector 2.5, 28 AWG
2	1	8-1971793-1	8P Plug Housing, Next Generation GI Connector 2.5
	1	8-1971798-1	8P Header Receptacle, Next Generation GI Connector 2.5
	8	1971795-1	Receptacle Contact 2.5 Pitch Next Generation GI Connector 2.5, 22 AWG
4	1	8-1971793-1	8P Plug Housing, Next Generation GI Connector 2.5
	8	1971795-1	Receptacle Contact 2.5 Pitch Next Generation GI Connector 2.5, 22 AWG
5	12	8-1971793-1	8P Plug Housing, Next Generation GI Connector 2.5
	12	8-1971798-1	8P Header Receptacle, Next Generation GI Connector 2.5
	24	1971795-1	Receptacle Contact 2.5 Pitch Next Generation GI Connector 2.5, 22 AWG
	24	1971795-1	Receptacle Contact 2.5 Pitch Next Generation GI Connector 2.5, 24 AWG
	24	1971795-1	Receptacle Contact 2.5 Pitch Next Generation GI Connector 2.5, 26 AWG
7	3	8-1971793-1	8P Plug Housing, Next Generation GI Connector 2.5
	3	8-1971798-1	8P Header Receptacle, Next Generation GI Connector 2.5
	24	1971795-1	Receptacle Contact 2.5 Pitch Next Generation GI Connector 2.5, 22 AWG
8	3	8-1971793-1	8P Plug Housing, Next Generation GI Connector 2.5
	3	8-1971798-1	8P Header Receptacle, Next Generation GI Connector 2.5
	24	1971795-1	Receptacle Contact 2.5 Pitch Next Generation GI Connector 2.5, 22 AWG
9	3	8-1971793-1	8P Plug Housing, Next Generation GI Connector 2.5
	3	8-1971798-1	8P Header Receptacle, Next Generation GI Connector 2.5
	24	1971795-1	Receptacle Contact 2.5 Pitch Next Generation GI Connector 2.5, 22 AWG
11	3	8-1971793-1	8P Plug Housing, Next Generation GI Connector 2.5
	3	8-1971798-1	8P Header Receptacle, Next Generation GI Connector 2.5
	24	1971795-1	Receptacle Contact 2.5 Pitch Next Generation GI Connector 2.5, 22 AWG
12	3	8-1971793-1	8P Plug Housing, Next Generation GI Connector 2.5
	3	8-1971798-1	8P Header Receptacle, Next Generation GI Connector 2.5
	24	1971795-1	Receptacle Contact 2.5 Pitch Next Generation GI Connector 2.5, 22 AWG
13	3	8-1971793-1	8P Plug Housing, Next Generation GI Connector 2.5
	3	8-1971798-1	8P Header Receptacle, Next Generation GI Connector 2.5
	24	1971795-1	Receptacle Contact 2.5 Pitch Next Generation GI Connector 2.5, 22 AWG
14	3	8-1971793-1	8P Plug Housing, Next Generation GI Connector 2.5
	3	8-1971798-1	8P Header Receptacle, Next Generation GI Connector 2.5
	24	1971795-1	Receptacle Contact 2.5 Pitch Next Generation GI Connector 2.5, 22 AWG
15	3	8-1971793-1	8P Plug Housing, Next Generation GI Connector 2.5
	3	8-1971798-1	8P Header Receptacle, Next Generation GI Connector 2.5
	24	1971795-1	Receptacle Contact 2.5 Pitch Next Generation GI Connector 2.5, 22 AWG
16	3	8-1971793-1	8P Plug Housing, Next Generation GI Connector 2.5
	3	8-1971798-1	8P Header Receptacle, Next Generation GI Connector 2.5
	24	1971795-1	Receptacle Contact 2.5 Pitch Next Generation GI Connector 2.5, 22 AWG

1.6. Qualification Test Sequence

Table 2 – Test Sequence

Test or Examination	Test Group (a)																			
	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20
	Test Sequence (b)																			
Confirmation of Product	1, 3	1, 4	1, 3	1, 3	1, 3	1, 4	1, 7	1, 7	1, 4	1, 3	1, 4	1, 4	1, 4	1, 4	1, 4	1, 4	1, 3	1, 3	1, 3	1, 4
Termination Resistance (Low Level)							2, 4, 6	2, 6	2, 5		2, 5	2, 5	2, 5	2, 5	2, 5	2, 5				2, 5
Dielectric Withstanding Voltage						3					7									
Insulation Resistance						2					6									
Temperature Rising					2															
Vibration (Low Frequency)							5													
Physical Shock							3													
Connector Mating Force								3												
Connector Unmating Force								4												
Receptacle Contact Insertion Force				2																
Contact Mating Force		2																		
Contact Unmating Force		3																		
Crimping Tensile Strength	2																			
Durability (Repeated Mating/Unmating)								5												
Housing Locking Strength			2																	
NH ₃																3				
Humidity-Temperature Cycling											3									
H ₂ S															3					
Thermal Shock									3											
Salt Spray												3								
Resistance to Cold														3						
Receptacle Contact Retention Force						5					8									
Heat Aging													3							
Post Retention Force																	2			
Solderability																		2		
Resistance to Soldering Heat																			2	
Hammering Shocks																				3
Housing Mating Strength										2										



NOTE

- (a) See Paragraph 1.5
- (b) Numbers indicate sequence which tests were performed.

1.7. Environmental Conditions

Unless otherwise stated, the following environmental conditions prevailed during testing:

Temperature: 15°C to 35°C
 Relative Humidity: 20% to 80%

2. SUMMARY OF TESTING

2.1. Confirmation of Product – All Test Groups

All specimens submitted for testing were representative of normal production lots. A Certificate of Conformance was issued by Product Assurance. Where specified, specimens were visually examined and no evidence of physical damage detrimental to product performance was observed.

2.2. Termination Resistance (Low Level) – Groups 7 thru 9 and 11 thru 16

All specimens met the 10 milliohm (mΩ) initial resistance requirement or 20 milliohm (mΩ) initial resistance found in 108-106077, Rev. D. LLCR summary data for each interval is shown in Table 3 through Table 11.

Table 3 – Group 7, Termination Resistance (mΩ)

	Test Data		
	Initial	After Physical Shock	After Vibration
Minimum	2.63	2.58	2.47
Maximum	3.72	4.48	10.58
Average	3.11	3.33	5.42
N	24	24	24
Requirement	10 (max)	20 (max)	20 (max)

Table 4 – Group 8, Termination Resistance (mΩ)

	Test Data	
	Initial	Final
Minimum	2.72	3.31
Maximum	3.58	5.99
Average	3.11	4.27
N	24	24
Requirement	10 (max)	20 (max)

Table 5 – Group 9, Termination Resistance (mΩ)

	Test Data	
	Initial	Final
Minimum	2.73	2.75
Maximum	3.31	3.67
Average	3.00	3.08
N	24	24
Requirement	10 (max)	20 (max)

Table 6 – Group 11, Termination Resistance (mΩ)

	Test Data	
	Initial	After Humidity-Temperature Cycling
Minimum	2.48	2.71
Maximum	3.26	5.42
Average	2.95	3.52
N	24	24
Requirement	10 (max)	20 (max)

Table 7 – Group 12, Termination Resistance (mΩ)

	Test Data	
	Initial	After Salt Spray
Minimum	2.61	2.96
Maximum	3.66	7.37
Average	3.12	4.02
N	24	24
Requirement	10 (max)	20 (max)

Table 8 – Group 13, Termination Resistance (mΩ)

	Test Data	
	Initial	After Heat Aging
Minimum	2.43	2.40
Maximum	3.17	3.53
Average	2.84	3.12
N	24	24
Requirement	10 (max)	20 (max)

Table 9 – Group 14, Termination Resistance (mΩ)

	Test Data	
	Initial	After Cold Storage
Minimum	2.65	2.70
Maximum	3.30	3.54
Average	2.98	2.99
N	24	24
Requirement	10 (max)	20 (max)

Table 10 – Test Group 15, Termination Resistance (mΩ)

	Test Data	
	Initial	After H ₂ S/Mixed Flowing Gas
Minimum	2.52	2.74
Maximum	3.31	5.06
Average	2.88	3.86
N	24	24
Requirement	10 (max)	20 (max)

Table 11 – Test Group 16, Termination Resistance (mΩ)

	Test Data	
	Initial	After NH ₃
Minimum	1.53	2.12
Maximum	2.96	5.45
Average	2.60	3.21
N	24	24
Requirement	10 (max)	20 (max)

2.3. Dielectric Withstanding Voltage – Group 11

All specimens in Test Group 11 met the requirement for dielectric withstanding voltage with a maximum current leakage of 5 mA and no dielectric breakdown or flashover occurring.

2.4. Insulation Resistance – Group 11

All specimens in Test Group 11 met the 500MΩ minimum requirement for insulation resistance found in Product Specification 108-106077, Rev. D. Insulation resistance summary data is shown in Table 12.

Table 12 – Group 11, Insulation Resistance (MΩ)

	Test Data
Minimum	850
Maximum	2140
Average	1320
N	12
Requirement	500

2.5. Temperature Rising – Group 5

All specimens met the 30°C maximum requirement for temperature rise when tested at their rated current. Temperature rising test summary data is shown in Table 13.

Table 13 – Group 5, Temperature Rising (°C)

	Test Data			
	1971795-1 on 22 AWG	1971795-1 on 24 AWG	1971795-1 on 26 AWG	1971795-1 on 28 AWG
Minimum	16.52	11.28	10.89	7.28
Maximum	16.65	12.78	11.5	9.71
Average	16.02	12.28	11.23	8.58
N	6	6	6	6
Requirement	30 (max)	30 (max)	30 (max)	30 (max)

2.6. Vibration (Low Frequency) – Group 7

No evident of physical damage was visible on any specimen after exposure to vibration.

2.7. Physical Shock – Group 7

No discontinuities greater than 1 μs were detected during physical shock testing. Following physical shock testing, no cracks, breaks, or loose parts on the specimens were visible.

2.8. Connector Mating Force – Group 8

All mating force measurements were less than maximum requirement of 2.94 N per contact. Connector mating force data is shown in Table 14.

Table 14 – Group 8, Connector Mating Force (N)

	Test Data
Minimum	1.40
Maximum	2.32
Average	1.83
N	5
Requirement	2.94 (max)

2.9. Connector Unmating Force – Group 8

All unmating force measurements were greater than the minimum requirement of 0.12 N per contact (initial unmating) and 0.08 N per contact (30th unmating). Connector unmating force data is shown in Table 15.

Table 15 – Group 8, Connector Unmating Force (N)

	Test Data	
	Initial	30 th Unmating
Minimum	2.51	2.31
Maximum	2.75	2.52
Average	2.61	2.39
N	3	3
Requirement	0.12 N (Min)	0.08 N (Min)

2.10. Receptacle Contact Insertion Force – Group 4

All receptacle contact insertion force values were less than the maximum requirement of 7.84 N. Receptacle contact insertion force data is shown in Table 16.

Table 16 – Group 4, Receptacle Contact Insertion Force (N)

	Test Data
Minimum	5.46
Maximum	7.64
Average	6.44
N	8
Requirement	7.84 (max)

2.11. Contact Mating Force – Group 2

All mating force values per pin were less than the maximum requirement of 2.94 N. Contact mating force summary data is shown in Table 17.

Table 17 – Group 2, Contact Mating Force (N)

	Test Data
Minimum	1.40
Maximum	2.32
Average	1.83
N	5
Requirement	2.94 (max)

2.12. Contact Unmating Force – Group 2

All unmating force values per pin were more than the minimum requirement of 0.12 N (first unmating) and 0.08 N (30th unmating). Contact unmating force summary data is shown in Table 18.

Table 18 – Group 2, Contact Unmating Force (N)

	Test Data	
	Initial Unmating	30 th Unmating
Minimum	1.51	0.59
Maximum	2.49	1.28
Average	1.87	0.84
N	5	5
Requirement	0.12 (min)	0.08 (min)

2.13. Crimping Tensile Strength – Group 1

All specimens met the minimum crimp tensile strength requirement. Crimp tensile strength summary data is shown in .

Table 19.

Table 19 – Group 1, Crimping Tensile Strength (N)

	Test Data			
	1971795-1 on 22 AWG	1971795-1 on 24 AWG	1971795-1 on 26 AWG	1971795-1 on 28 AWG
Minimum	57.01	34.75	28.88	19.18
Maximum	77.12	56.13	40.12	27.08
Average	69.12	52.11	36.24	22.45
N	10	10	10	10
Requirement	49.0 (min)	29.4 (min)	19.6 (min)	9.8 (min)

2.14. Durability (Repeated Mating/Unmating) – Group 8

No evidence of physical damage detrimental to product performance was visible as a result of repeated mating and unmating for 30 cycles.

2.15. Housing Locking Strength – Group 3

Refer to Qualification Test Report 501-106077 Rev B for results for Test Group 3.

 2.16. NH₃ – Group 16

No evidence of physical damage was visible on any specimen after exposure to NH₃.

2.17. Humidity-Temperature Cycling – Group 11

No evidence of physical damage was visible on any specimen after exposure to temperature-humidity cycling.

 2.18. H₂S – Group 15

No evidence of physical damage detrimental to product performance was visible as a result of exposure to H₂S.

2.19. Thermal Shock – Group 9

No evidence of physical damage was visible after thermal shock testing.

2.20. Salt Spray – Group 12

No evidence of physical damage detrimental to product performance was visible as a result of exposure to salt spray solution.

2.21. Resistance to Cold – Group 14

No evidence of physical damage detrimental to product performance was visible as a result of exposure to cold storage at –30°C for 96 hours

2.22. Receptacle Contact Retention Force – Group 11

All receptacle contact retention force values were more than the minimum requirement of 14.7 N. Receptacle contact retention force data is shown in Table 1620.

Table 20 – Group 11, Receptacle Contact Retention Force (N)

	Test Data
Minimum	40.03
Maximum	47.31
Average	44.09
N	8
Requirement	14.7 (min)

- 2.23. Heat Aging – Group 13
No evidence of physical damage detrimental to product performance was visible as a result of exposure to heat aging at 105°C for 96 hours.
- 2.24. Post Retention Force – Group 17
Refer to Qualification Test Report 501-106077 Rev B for results for Test Group 17.
- 2.25. Solderability – Group 18
Refer to Qualification Test Report 501-106077 Rev B for results for Test Group 18.
- 2.26. Resistance to Soldering Heat – Group 19
Refer to Qualification Test Report 501-106077 Rev B for results for Test Group 19.
- 2.27. Hammering Shocks – Group 20
Refer to Qualification Test Report 501-106077 Rev B for results for Test Group 20.
- 2.28. Housing Mating Strength – Group 10
Refer to Qualification Test Report 501-106077 Rev B for results for Test Group 10.

3. TEST METHODS

- 3.1. Confirmation of Product
Testing was performed in accordance with EIA-364-18B. Specimens were visually examined and no evidence of physical damage detrimental to product performance was observed.
- 3.2. Termination Resistance (Low Level)
Testing was performed in accordance with EIA 364-23 using a test current of 100 mA and a test voltage limited to 20mV.
- 3.3. Dielectric Withstanding Voltage
Testing was performed in accordance with EIA-364-20D. A test potential of 1.1 kVAC was applied by the adjacent contacts of mated specimens. This potential was applied for 1 minute and then returned to zero.
- 3.4. Insulation Resistance
Testing was performed in accordance with EIA-364-21E. Insulation resistance was measured between adjacent contacts of mated specimens. A test voltage of 500 volts DC was applied for 1 minute before the resistance was measured.
- 3.5. Temperature Rising
Testing was performed in accordance with EIA-364-70C. Thermocouples were soldered to each test specimen. Test specimens were connected in series in a draft free chamber. Each test current was applied until specimen temperatures were stable, then recorded. Stability occurred when 3 consecutive temperature measurements taken at 5 minute intervals did not differ by more than 1°C.
- 3.6. Vibration (Low Frequency)
The test specimens were subjected to a sinusoidal vibration test in accordance with specification MIL-STD-202-2002, Method 201A. The parameters consist of simple harmonic motion having an amplitude of 1.52 mm. The vibration frequency was varied logarithmically between the approximate limits of 10 to 55 Hertz (Hz). The entire frequency range of 10 to 55 Hz and return to 10 Hz was traversed in

approximately 1 minute. This cycle was performed in all three mutually perpendicular axes for a total period of approximately 2 hours in each plane.

3.7. Physical Shock

Testing was performed in accordance with MIL-STD-202-2002, Method 213, Condition A. Mated specimens were subjected to a physical shock test having a half-sine waveform of 50 gravity units (g peak) and a duration of 11 milliseconds. Three shocks in each direction were applied along the 3 mutually perpendicular planes for a total of 18 shocks. Specimens were monitored for discontinued of 1 μ s or greater using a current of 100 mA.

3.8. Connector Mating Force

Testing was performed in accordance with EIA-364-13E. Mating force was measured with a tensile/compression machine. The cap housing was held in a vice mounted to an X-Y table rigidly clamped to the base of the tensile/compression testing machine. The plug housing was placed onto the cap housing with the latching feature disabled. Wire leads were supported to prevent unnecessary stress while mating force was measured. The moveable crosshead was lowered at a rate of 100 mm/min until the specimen was fully mated. The peak force required to mate the connector was recorded.

3.9. Connector Unmating Force

Testing was performed in accordance with EIA-364-13E. Unmating force was measured with a tensile/compression machine. The cap housing was held in a vice mounted to an X-Y table rigidly clamped to the base of the tensile/compression testing machine with the latch disengaged. Wire leads were supported to prevent unnecessary stress while mating force was measured. The moveable crosshead was raised at a rate of 100 mm/min until the specimen was fully unmated. The peak force required to unmate the connector was recorded.

3.10. Receptacle Contact Insertion Force – Group 4

Testing was performed in accordance with 108-106077, Rev D. Contact insertion force was measured by applying an increasing force to each contact using a tensile/compression device with a rate of travel at 25.4 mm per minute until the contact was properly seated in the housing.

3.11. Contact Mating Force – Group 2

Testing was performed in accordance with 108-106077, Rev D.

3.12. Contact Unmating Force – Group 2

Testing was performed in accordance with 108-106077, Rev D.

3.13. Crimping Tensile Strength – Group 1

Testing was performed in accordance with 108-106077, Rev D. The force load was applied to each specimen was applied to each specimen using a tensile/compression device with the rate of travel at 100 mm per minute.

3.14. Durability (Repeated Mating/Unmating)

Testing was performed by mating and unmating test specimens for 30 cycles.

3.15. Housing Locking Strength

Refer to Qualification Test Report 501-106077 Rev B for results of housing locking strength test.

3.16. NH₃

Testing was performed in accordance with 108-106077, Rev. D. Mated specimens were subjected to a 3% NH₃ solution environment for 7 hours.

3.17. Humidity-Temperature Cycling

Testing was performed in accordance with EIA-364-31C. Mated test specimens were subjected to 10 cycles (10 days) of humidity with temperature cycling between the temperature range of 25°C and 65°C, humidity range of 90-98% RH with cold exposure of -10°C .

3.18. H₂S

Testing was performed in accordance with 108-106077, Rev. D. Mated specimens were subjected to a 3±1 ppm H₂S environment for 96 hours at a temperature of 40±2°C.

3.19. Thermal Shock

Testing was performed in accordance with EIA-364-32F. Mated specimens were subjected to 25 cycles of thermal shock with each cycle consisting of 30 minute dwells at -55°C and 85°C. The transition between temperature was less than 5 minutes.

3.20. Salt Spray

Testing was performed in accordance with EIA-364-26C. Mated specimens were subjected to a 5% salt spray environment for 48 hours. The temperature of the box was maintained at 35°C while the pH of the salt solution was between 6.5 and 7.2.

3.21. Resistance to Cold

Testing was performed in accordance with IEC 60512-11-10-2002. Mated specimens were placed in a cold storage unit at a temperature of -30°C for 96 hours.

3.22. Receptacle Contact Retention Force

Testing was performed in accordance with 108-106077, Rev D. Contact retention force was measured by applying an increasing force to each contact using a tensile/compression device with a rate of travel at 25.4 mm per minute until the contact was properly out of the housing.

3.23. Heat Aging

Testing was performed in accordance with IEC 60512-11-9-2002. Mated specimens were placed in an air-circulating oven at a temperature of 105°C for 96 hours.

3.24. Post Retention Force

Refer to Qualification Test Report 501-106077 Rev B for results of post retention force test.

3.25. Solderability

Refer to Qualification Test Report 501-106077 Rev B for results of solderability test.

3.26. Resistance to Soldering Heat

Refer to Qualification Test Report 501-106077 Rev B for results of resistance to soldering heat test.

3.27. Hammering Shocks

Refer to Qualification Test Report 501-106077 Rev B for results of hammering shocks test.

3.28. Housing Mating Strength

Refer to Qualification Test Report 501-106077 Rev B for results of housing mating strength test.

4. CALIBRATION

4.1. Calibration Statement

All testing equipment contains a calibration number and is calibrated and traceable through TE Connectivity (TE).